

**Search Notes**

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Examiner

Hai L. Nguyen

Applicant(s)/Patent under  
Reexamination

MASON, JAMES STEPHEN

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
331	16,17	4/18/2005	HLN
327	311,312	—	—
327	551-559	—	—

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	4/18/2005	HLN